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Applicants: Shunpei YAMAZAKI et al.

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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
EL	0 486 284 A2	05/20/1992	European			Engl.	
EL	63-100777	05/02/1988	Japan			Abst.	

OTHER DOCUMENT (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial	
EL	Yoshikawa et al., "Estimation of a Stress of Si by Microscopic Raman Spectroscopy", Jan 1992, pp. 35-38, The TRC News No. 38 Partial Translation

Examiner

Date Considered

2/15/01

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